



FORM PTO 1449 (Modified)  
LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENT  
Page 1 of 1

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SERIAL NO.

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APPLICANT: EDWARD J. GRENCHUS JR

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GROUP

3623

#### OTHER ART

EXAMINER INITIALS		BIBLIOGRAPHIC DATA (Author, Title, Date, Pertinent Pages, Etc.)
/DCR/	CA	SODHI, MANBIR S. AND WINSTON A. KNIGHT. "MODELS AND TOOLS FOR END-OF-LIFE PRODUCT MANAGEMENT," <i>The Demanufacturing of Electronic Equipment, October 29-31, 1997, Volume 1</i> . Conference Coordinated by: Florida Educational Seminars, Inc. Boca Raton, Florida. 1-9.
/DCR/	CB	MAHONEY, JOSEPH P. "THE RISKS AND REWARDS OF ELECTRONICS RECYCLING NEEDS/BENEFITS ANALYSIS FOR OEM's AND ELECTRONICS RECYCLING COMPANIES," <i>The Demanufacturing of Electronic Equipment, October 28-30, 1998, Volume 2</i> . Conference Coordinated by Florida Educational Seminars, Inc. Boca Raton, Florida. 1-4.
/DCR/	CC	LIMAYE, KETAN AND REGGIE J. CAUDILL. "SYSTEM SIMULATION AND MODELING OF ELECTRONICS DEMANUFACTURING FACILITIES," <i>IEEE International Symposium on Electronics &amp; the Environment, Danvers, Massachusetts, May 11-13, 1999</i> . 238-243.
/DCR/	CD	DAS, SANCHOY K. AND SHIBU MATTHEW. "CHARACTERIZATION OF MATERIAL OUTPUTS FROM AN ELECTRONICS DEMANUFACTURING FACILITY," <i>IEEE International Symposium on Electronics &amp; the Environment, Danvers, Massachusetts, May 11-13, 1999</i> . 251-256.
/DCR/	CE	VEERAKAMOLMAL, PITIPONG AND SURENDRA M. GUPTA. "A COMBINATORIAL COST-BENEFIT ANALYSIS METHODOLOGY FOR DESIGNING MODULAR ELECTRONIC PRODUCTS FOR THE ENVIRONMENT." <i>IEEE International Symposium on Electronics &amp; the Environment, Danvers, Massachusetts, May 11-13, 1999</i> . 268-273.

EXAMINER	/Dave Robertson/ (04/19/2007)	DATE CONSIDERED	04/19/2007
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.